



National Standards Authority of Ireland

IRISH STANDARD

**I.S. EN 61751:1999**

ICS 31.260

**LASER MODULES USED FOR  
TELECOMMUNICATION RELIABILITY  
ASSESSMENT (IEC 61751:1998)**

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**EUROPEAN STANDARD**  
**NORME EUROPÉENNE**  
**EUROPÄISCHE NORM**

**EN 61751**

April 1998

ICS 31.260

Descriptors: Laser modules, telecommunication, reliability

English version

**Laser modules used for telecommunication**  
**Reliability assessment**  
**(IEC 61751:1998)**

Modules laser utilisés pour les  
télécommunications  
Evaluation de la fiabilité  
(CEI 61751:1998)

Lasermodule für  
Telekommunikationsanwendungen  
Zuverlässigkeitsbewertung  
(IEC 61751:1998)

This European Standard was approved by CENELEC on 1998-04-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Czech Republic, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

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### **Foreword**

The text of document 86/115/FDIS, future edition 1 of IEC 61751, prepared by SC 47C, Optoelectronic, display and imaging devices, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61751 on 1998-04-01.

The following dates were fixed:

- latest date by which the EN has to be implemented  
at national level by publication of an identical  
national standard or by endorsement (dop) 1999-01-01
- latest date by which the national standards conflicting  
with the EN have to be withdrawn (dow) 2001-01-01

Annexes designated "normative" are part of the body of the standard.

Annexes designated "informative" are given for information only.

In this standard, annexes A and ZA are normative and annex B is informative.

Annex ZA has been added by CENELEC.

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### **Endorsement notice**

The text of the International Standard IEC 61751:1998 was approved by CENELEC as a European Standard without any modification.

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**Annex ZA (normative)****Normative references to international publications  
with their corresponding European publications**

This European Standard incorporates by dated or undated reference, provisions from other publications. These normative references are cited at the appropriate places in the text and the publications are listed hereafter. For dated references, subsequent amendments to or revisions of any of these publications apply to this European Standard only when incorporated in it by amendment or revision. For undated references the latest edition of the publication referred to applies (including amendments).

NOTE: When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-2-1	1990	Environmental testing Part 2: Tests Tests A: Cold	EN 60068-2-1	1993
IEC 60068-2-14	1984	Part 2: Tests Test N: Change of temperature	HD 323.2.14 S2 <sup>1)</sup>	1987
IEC 60747-1	1983	Semiconductor devices Discrete devices and integrated circuits Part 1: General	-	-
+ A3	1996		-	-
IEC 60747-12-2	1995	Part 12: Optoelectronic devices Section 2: Blank detail specification for laser diode modules with pigtail for fibre optic systems and sub-systems	-	-
IEC 60749	1996	Semiconductor devices Mechanical and climatic test methods	-	-
ISO 9000	series	Quality management and quality assurance standards	EN ISO 9000	series
MIL-STD-883	1985	Test Methods and Procedures for Microelectronics	-	-

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1) HD 323.2.14 S2 includes A1:1986 to IEC 60068-2-14.



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